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<b>LIST OF PRIOR ART CITED BY APPLICANT</b> <b>(PTO-1449)</b>			ATTY. DOCKET NO. <b>K-195B</b>		APPLN. SERIAL NO. <b>10/669,445</b>	
			APPLICANT(S) <b>Jae K. KIM et al.</b>			
			FILING DATE <b>September 25, 2003</b>		GROUP <b>3726</b>	
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
EC	2,531,225	11/1950	LE TOURNEAU			
	2,656,702	10/1953	CHAPIN			
	3,194,032	7/1965	VON BRIMER			
	4,686,399	8/1987	IMORI ET AL.			
	5,966,379	10/1999	PHILLIPS ET AL.			
EC	6,049,930	4/2000	HISANO ET AL.			
<b>U.S. PATENT APPLICATION PUBLICATIONS</b>						
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	
<b>U.S. PATENT APPLICATIONS</b>						
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	
<b>FOREIGN PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes      No
EC	2,006,836	5/1979	UK			
	2,202,867	10/1988	UK			
EC	95/17543	6/1995	WIPO			
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)</b>						
EXAMINER	<i>Eric L. Angst</i>		DATE CONSIDERED		<i>9/5/06</i>	

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## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
EC	5,586,455	12/1996	IMAI			
EC	6,006,553	12/1999	LEE ET AL.			
EC	6,023,839	2/2000	KINOSHITA			
EC	6,339,275	1/2002	KATAGIRI			
EC	6,661,550	12/2003	KONNO ET AL.			

## U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS

## U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
EC	31 05 318	8/1982	GERMANY			Abst	
EC	36 34 214	4/1998	GERMANY			Abst	
EC	36 14 703	11/1986	GERMANY			Abst	
EC	60-5197	1/1985	JAPAN				X
EC	2,189,511	10/1987	UK				
EC	2,261,881	6/1993	UK			Abst	
EC	0 198 554	10/1986	EPO				
EC	0 354 158	2/1990	EPO				
EC	0 374 519	6/1990	EPO				
EC	2,272,913	6/1994	UK				
EC	2,322,240	6/1998	UK				

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

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	6/5/2006

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## U.S. PATENT DOCUMENTS

## U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS
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## U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

## FOREIGN PATENT DOCUMENTS

**OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)**

**EXAMINER**

*Erica*

**DATE CONSIDERED**

6/5/2006

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